

**Notice of References Cited**

Application/Control No.

10/511,751

Applicant(s)/Patent Under  
Reexamination  
MAEDA ET AL.

Examiner

YONAS BAYOU

Art Unit

2434

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0190044	10-2003	Higashi et al.	380/201
*	B	US-2001/0029526	10-2001	Yokoyama et al.	709/218
*	C	US-5,909,257	06-1999	Ohishi et al.	348/726
*	D	US-2001/0034834	10-2001	Matsuyama et al.	713/156
*	E	US-6,044,154	03-2000	Kelly, Tadhg	713/155
*	F	US-5,870,477	02-1999	Sasaki et al.	713/165
*	G	US-6,505,347	01-2003	Kaneko et al.	725/39
*	H	US-5,237,610	08-1993	Gammie et al.	380/228
*	I	US-6,615,349	09-2003	Hair, Arthur R.	713/165
*	J	US-6,134,659	10-2000	Sprong et al.	713/190
*	K	US-2004/0059911	03-2004	Ueno, Takafumi	713/165
*	L	US-5,619,700	04-1997	Abe, Yoshinari	717/122
*	M	US-5,754,651	05-1998	Blatter et al.	380/241

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	V					
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	X					

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